Am27S45/27S45A/27S45SA
Am27S47/27S47A/27S47SA

16,384-Bit (2048x8) Bipolar Registered PROM
with Programmable INITIALIZE Input

Advanced Micro Devices

DISTINCTIVE CHARACTERISTICS

- "SA" version offers superior performance with 25 ns setup time and 10 ns clock-to-output delay
- Slim, 24-pin, 300-mil lateral center package occupies approximately 1/3 the board space required by standard discrete PROM and register
- Consumes approximately 1/2 the power of separate PROM/register combination for improved system reliability
- Versatile programmable asynchronous or synchronous enable for simplified word expansion
- Buffered common $\overline{\text{INITIALIZE}}$ input either asynchronous (Am27S45) or synchronous (Am27S47)
- Platinum-Silicide fuses guarantee high reliability, fast programming and exceptionally high programming yields (typ. > 98%)

GENERAL DESCRIPTION

The Am27S45 and the Am27S47 (2048-words by 8-bits) are fully decoded, Schottky array, TTL Programmable Read-Only Memories (PROMs), incorporating D-type master-slave data registers on chip. These devices have three-state outputs compatible with low-power Schottky bus standards capable of satisfying the requirements of a variety of microprogrammable controls and state machines.

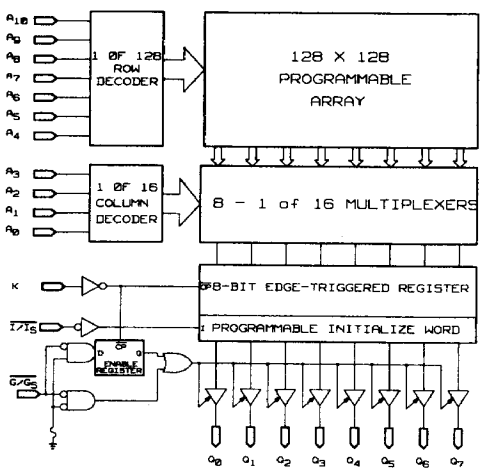
These devices contain an 8-bit parallel data register in the array-to-output path which allows PROM data to be stored while other data is being addressed. This meets the requirements for pipelined microprogrammable control stores where instruction execute and instruction fetch are performed in parallel.

To Offer the system designer maximum flexibility, these devices contain a user programmable asynchronous or synchronous output enable. The unprogrammed state of the enable pin operates as an Asynchronous Enable ($\overline{G}$) input. An architecture word permits the programming of the functionality of this pin to Synchronous Enable ($\overline{G_S}$).

These devices contain a single pin initialize function capable of loading any arbitrary microinstruction for system interrupt or initialization. On the Am27S45 this function operates asynchronously, independent of clock. The Am27S47 provides synchronous operation of this function.

If the architecture has been programmed to synchronous enable, upon power-up the outputs ($Q_0 - Q_7$) will be in a floating or high-impedance state.

BLOCK DIAGRAM



BD006381

Publication #	Rev.	Amendment
03186	D	/0

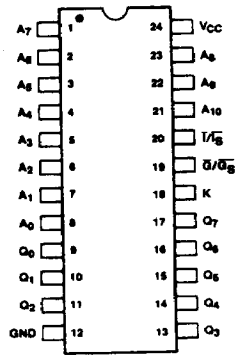
Issue Date: January 1989

PRODUCT SELECTOR GUIDE

Part Number Asynchronous Initialize	27S45SA		27S45A		27S45	
Part Number Synchronous Initialize	27S47SA		27S47A		27S47	
Address Setup Time (ns)	25	28	40	45	45	50
Clock-to-Output Delay (ns)	10	12	20	25	25	30
Operating Range	C	M	C	M	C	M

CONNECTION DIAGRAMS
Top View

DIPs*



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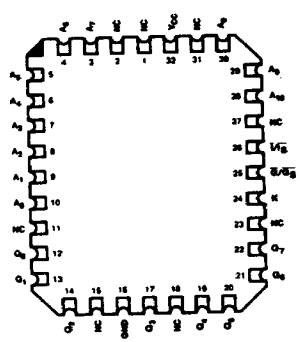
LCCs**



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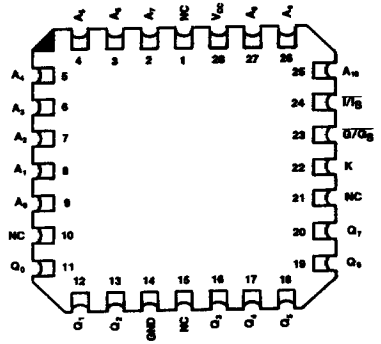

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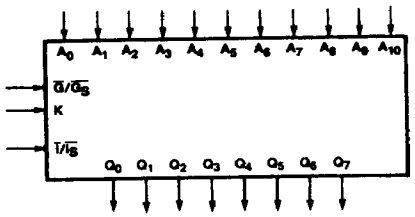
Note: Pin 1 is marked for orientation.
*Also available in a 24-pin Flatpack. Pinout identical to DIPs.
**Also available in a 28-pin Square Plastic Leaded Chip Carrier. Pinout identical to LCC.

LOGIC SYMBOL



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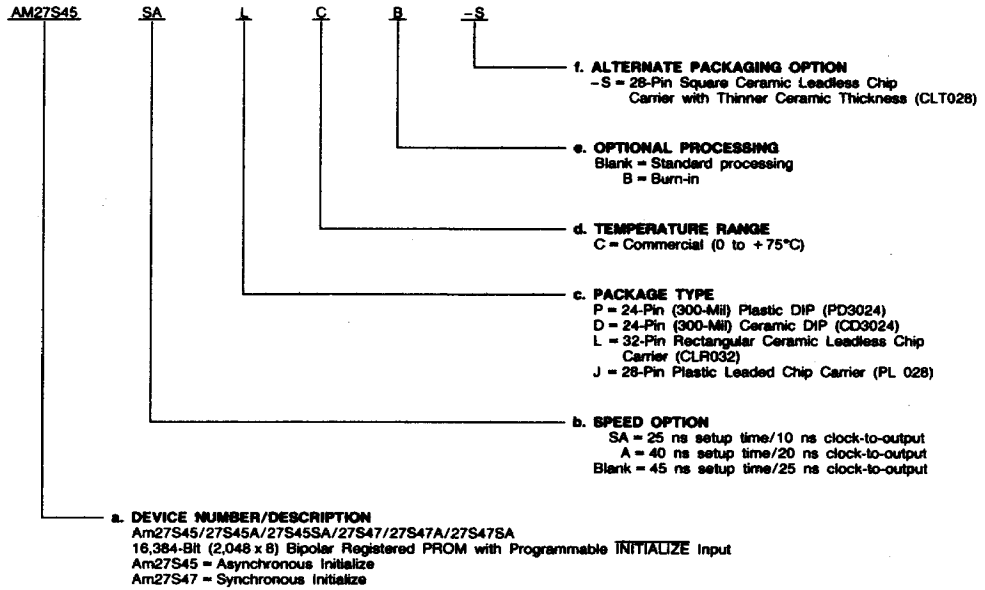
ORDERING INFORMATION

Standard Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of: **a. Device Number**
b. Speed Option (if applicable)
c. Package Type
d. Temperature Range
e. Optional Processing
f. Alternate Packaging Option



Valid Combinations	
AM27S45SA	DC, DCB, PC, PCB, LC, LCB, LC-S, LCB-S, JC, JCB
AM27S45A	
AM27S45	
AM27S47SA	
AM27S47A	
AM27S47	

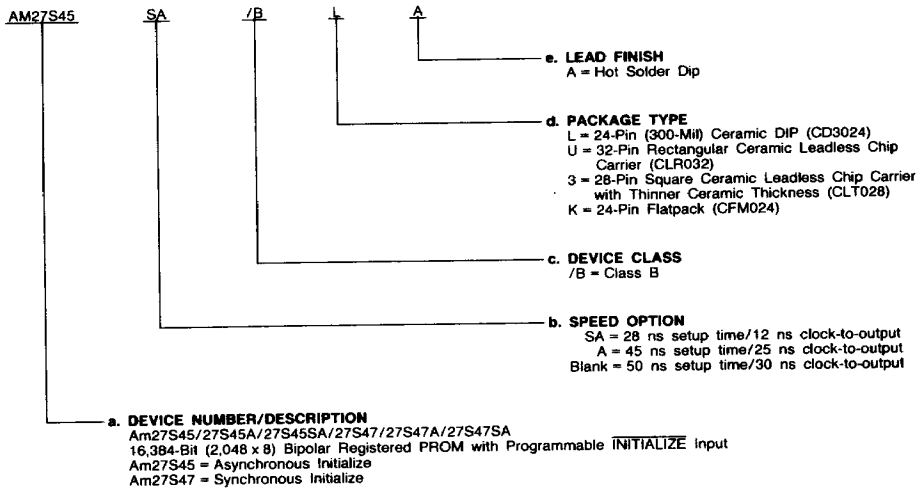
Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

MILITARY ORDERING INFORMATION

APL Products

AMD products for Aerospace and Defense applications are available in several packages and operating ranges. APL (Approved Products List) products are fully compliant with MIL-STD-883C requirements. The order number (Valid Combination) for APL products is formed by a combination of: **a. Device Number**
b. Speed Option (if applicable)
c. Device Class
d. Package Type
e. Lead Finish



Valid Combinations	
AM27S45SA	/BLA, /BKA, /BUA, /B3A
AM27S45A	
AM27S45	
AM27S47SA	
AM27S47A	
AM27S47	

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations or to check for newly released valid combinations.

Group A Tests

Group A tests consist of Subgroups 1, 2, 3, 7, 8, 9, 10, 11.

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MILITARY BURN-IN

Military burn-in is in accordance with the current revision of MIL-STD-883, Test Method 1015, Conditions A through E. Test conditions are selected at AMD's option.

PIN DESCRIPTION

$A_0 - A_{10}$ Address (Input)
The 11-bit field presented at the address inputs selects one of 2048 memory locations to be read from.

K Clock (Input)
The clock is used to load data into the parallel registers from the memory array. Data transfer occurs on the LOW-to-HIGH transition of K.

$Q_0 - Q_7$ Data Output Port
Parallel data output from the pipeline register. The disabled state of these outputs is floating or high impedance.

$\overline{I}$ Asynchronous Initialize (Input) (Am27S45)
Control pin used to initialize the output data registers from a programmable word independent of K. This can be used to generate any arbitrary microinstruction for system interrupt or initialization.

$\overline{I_S}$ Synchronous Initialize (Input) (Am27S47)
Control pin used to initialize the output data registers from a programmable word in conjunction with K. This can be used to generate any arbitrary microinstruction for system interrupt or initialization.

V_{CC} Device Power Supply Pin
The most positive of the logic power supply pins.

GND Device Power Supply Pin
The most negative of the logic power supply pins.

This device contains a single-bit architecture word which, according to programming, will provide one of the following functions.

$\overline{G}$ Asynchronous Output Enable (Input)
Provides direct control of the Q-output, three-state drivers independent of K.

$\overline{G_S}$ Synchronous Output Enable (Input)
Controls the state of the Q-output, three-state drivers in conjunction with K. This is useful where more than one registered PROM is bussed together for word-depth expansion. In this case, the enable becomes the most significant address bit and, as such, must be synchronized with the data.

FUNCTIONAL DESCRIPTION

The Am27S45A/45 and Am27S47A/47 are Schottky TTL programmable read only memories (PROMs) incorporating true D-type, master-slave data registers on chip. These devices feature the versatile 2048-word by 8-bit organization and are available with three-state outputs. Designed to optimize system performance, these devices also substantially reduce the cost and size of pipelined microprogrammed systems and other designs where accessed PROM data is temporarily stored in a register. The Am27S45A/45 and Am27S47A/47 also offer maximum flexibility for system design by providing either synchronous or asynchronous initialize, and synchronous or asynchronous output enable.

When V_{CC} power is first applied, the state of the outputs will depend on whether the enable has been programmed to be a synchronous or asynchronous enable. If the synchronous enable ($\overline{G_S}$) is being used, the register will be in the set condition causing the outputs (Q_0 to Q_7) to be in the OFF or high-impedance state. If the asynchronous enable ($\overline{G}$) is being used, the outputs will come up in the OFF or high-impedance state only if the enable ($\overline{G}$) input is at a logic HIGH level. Reading data is accomplished by first applying the binary word address to the address inputs (A_0 through A_{10}) and a logic LOW to the enable input. During the address setup time, the stored data is accessed and loaded into the master flip-flops of the data register. Upon the next LOW-to-HIGH transition of the clock input (K), data is transferred to the slave flip-flops which drive the output buffers, and the accessed data will appear at the outputs (Q_0 through Q_7). If the asynchronous enable ($\overline{G}$) is being used, the outputs may be disabled at any time by switching the enable to a logic HIGH, and may be returned to the active state by switching the enable back to the logic LOW state. For devices using the synchronous enable ($\overline{G_S}$), the outputs will go into the OFF or high-impedance state upon the next positive clock edge after the synchronous enable input is switched to a HIGH level. If the synchronous enable pin is switched to a logic LOW, the next positive clock edge will return the output to the active state. Following a positive clock edge, the address and synchronous enable inputs are free to change, since no change in the output will occur until the next LOW-to-HIGH transition of the clock. This unique feature allows the PROM decoders and sense amplifiers to access the next location while previously addressed data remains stable on the outputs.

The on-chip edge-triggered register simplifies system timing since the PROM clock may be derived directly from the system clock without introducing dangerous race conditions. Other register timing requirements are similar to those of standard Schottky registers and are easily implemented.

These devices also contain a built-in initialize function. When activated, the initialize control input ($\overline{I}$) causes the contents of an additional (2049th) 8-bit word to be loaded into the on-chip register. This extra word is user programmable. Since each bit is individually programmable, the initialize function can be used to load any desired combination of HIGHs and LOWs into the register. In the unprogrammed state, activating $\overline{I}$ will perform a register CLEAR (all outputs LOW). If all bits of the initialize word are programmed, activating $\overline{I}$ performs a register PRESET (all outputs HIGH).

This ability to tailor the initialize outputs to the system requirements simplifies system design and enhances performance. The initialize function is useful during power up and timeout sequences. This flexible feature can also facilitate implementation of other sophisticated functions such as a built-in "jump-start" address.

The Am27S45A/45 has an asynchronous initialize input ($\overline{I}$). Applying a LOW to the $\overline{I}$ input causes an immediate load of the programmed initialize word into the master and slave flip-flops of the register independent of all other inputs (including K). The initialize data will appear at the device outputs after the outputs are enabled by bringing the asynchronous enable ($\overline{G}$) LOW.

The Am27S47A/47 has a synchronous $\overline{I_S}$ input. Applying a LOW to the $\overline{I_S}$ input causes an immediate load of the programmed initialize word into the master flip-flops of the register only independent of all other inputs (including K). To bring this data to the outputs of a device with a synchronous enable, the synchronous enable ($\overline{G_S}$) should be held LOW until the next LOW-to-HIGH transition of the clock (K). For a device with an asynchronous enable, the data will appear at the device outputs after the next LOW-to-HIGH clock transition if the enable ($\overline{G}$) is held LOW.

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ABSOLUTE MAXIMUM RATINGS

Storage Temperature ..... −65 to +150°C
Ambient Temperature with
Power Applied ..... −55 to +125°C
Supply Voltage ..... −0.5 V to +7.0 V
DC Voltage Applied to Outputs
(Except During Programming) ..... −0.5 V to +V_{CC} Max.
DC Voltage Applied to Outputs
During Programming ..... 21 V
Output Current into Outputs During
Programming (Max. Duration of 1 sec.) ..... 250 mA
DC Input Voltage ..... −0.5 V to +5.5 V
DC Input Current ..... −30 mA to +5 mA

Stresses above those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

OPERATING RANGES

Commercial (C) Devices
Ambient Temperature (T_A) ..... 0 to +75°C
Supply Voltage (V_{CC}) ..... +4.75 V to +5.25 V

Military (M) Devices*
Case Temperature (T_C) ..... −55 to +125°C
Supply Voltage (V_{CC}) ..... +4.5 V to +5.5 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

*Military product 100% tested at T_C = +25°C, +125°C, and −55°C.

DC CHARACTERISTICS over operating range unless otherwise specified (for APL Products, Group A, Subgroups 1, 2, 3 are tested unless otherwise noted)

Parameter Symbol	Parameter Description	Test Conditions			Min.	Typ.	Max.	Unit
V_{OH}	Output HIGH Voltage	V_{CC} = Min., I_{OH} = −2.0 mA V_{IN} = V_{IH} or V_{IL}			2.4			V
V_{OL}	Output LOW Voltage	V_{CC} = Min., I_{OL} = 16 mA V_{IN} = V_{IH} or V_{IL}					0.50	V
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs (Note 1)			2.0			V
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs (Note 1)					0.8	V
I_{IL}	Input LOW Current	V_{CC} = Max., V_{IN} = 0.45 V					−0.250	mA
I_{IH}	Input HIGH Current	V_{CC} = Max., V_{IN} = V_{CC}					40	μA
I_{SC}	Output Short-Circuit Current	V_{CC} = Max., V_{OUT} = 0.0 V (Note 2)			−20		−90	mA
I_{CC}	Power Supply Current	Am27S45/Am27S47 Standard & "A" versions V_{CC} = Max., All inputs = 0.0 V					185	mA
		Am27S45/Am27S47 "SA" version only V_{CC} = Max., All inputs = 0.0 V (Note 5)	COM'L	T_A = 0°C			195	
				T_A = 25°C			190	
				T_A = 75°C			175	
			MIL	T_C = −55°C			210	
				T_C = 25°C			190	
				T_C = 125°C			160	
V_I	Input Clamp Voltage	V_{CC} = Min., I_{IN} = −18 mA					−1.2	V
I_{CEX}	Output Leakage Current	V_{CC} = Max. $V_{\overline{G}}$ = 2.4 V	(Note 3)	V_O = V_{CC}			40	μA
				V_O = 0.4 V			−40	
C_{IN}	Input Capacitance	V_{IN} = 2.0 V @ f = 1 MHz (Note 4) V_{CC} = 5.00 V; T_A = 25°C				5		pF
C_{OUT}	Output Capacitance	V_{OUT} = 2.0 V @ f = 1 MHz (Note 4) V_{CC} = 5.00 V; T_A = 25°C				12		

Notes: 1. V_{IL} and V_{IH} are input conditions of output tests and are not themselves directly tested. V_{IL} and V_{IH} are absolute voltages with respect to device ground and include all overshoots due to system and/or tester noise. Do not attempt to test these values without suitable equipment.
2. Only one output should be shorted at a time. Duration of the short circuit should not be more than one second.
3. For devices using the synchronous enable, the device must be clocked after applying these voltages to perform this measurement.
4. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where capacitance may be affected.
5. I_{CC} limits at temperature extremes are guaranteed by correlation to +25°C test limits.

SWITCHING CHARACTERISTICS over operating ranges unless otherwise specified (for APL Products, Group A, Subgroups 9, 10, 11 are tested unless otherwise noted*) (Note 1)

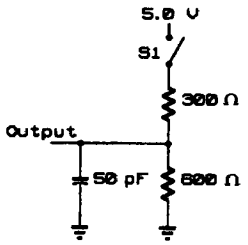
No.	Parameter Symbol	Parameter Description		Am27S45SA/ Am27S47SA Min.	Am27S45SA/ Am27S47SA Max.	Am27S45A/ Am27S47A Min.	Am27S45A/ Am27S47A Max.	Am27S45/ Am27S47 Min.	Am27S45/ Am27S47 Max.	Unit
1	TAVKH	Address to K HIGH Setup Time	COM'L	25		40		45		ns
			MIL	28		45		50		
2	TKHAX	Address to K HIGH Hold Time	COM'L	0		0		0		ns
			MIL	0		0		0		
3	$TKHQV_1$	Delay from K HIGH to Output Valid, for initially active outputs (HIGH or LOW) (Note 7)	COM'L	4	10		20		25	ns
			MIL	4	12		25		30	
4	TKHKL TKLKH	K Pulse Width (HIGH or LOW)	COM'L	15		20		20		ns
			MIL	20		20		20		
5	TGLQV	Asynchronous Output Enable LOW to Output Valid (HIGH or LOW) (Note 3)	COM'L		17		25		30	ns
			MIL		20		30		35	
6	TGHQZ	Asynchronous Output Enable HIGH to Output Hi-Z (Notes 2 & 3)	COM'L		17		25		30	ns
			MIL		20		30		35	
7	TGSVKH	$\overline{GS}$ to K HIGH Setup Time (Note 4)	COM'L	10		15		15		ns
			MIL	15		15		15		
8	TKHGSX	$\overline{GS}$ to K HIGH Hold Time (Note 4)	COM'L	5		5		5		ns
			MIL	5		5		5		
9	TKHQV2	Delay from K HIGH to Output Valid, for initially Hi-Z outputs (Note 4)	COM'L		17		25		30	ns
			MIL		20		30		35	
10	TKHQZ	Delay from K HIGH to Output Hi-Z (Notes 2 & 4)	COM'L		17		25		30	ns
			MIL		20		30		35	
11	TILQV	Delay from $\overline{I}$ LOW to Output Valid (HIGH or LOW) (Note 5)	COM'L		17		30		35	ns
			MIL		20		35		40	
12	TIHKH	Asynchronous $\overline{I}$ Recovery Time (Note 5)	COM'L	17		20		20		ns
			MIL	20		20		20		
13	TILIH	Asynchronous $\overline{I}$ Pulse Width (Note 5)	COM'L	15		25		25		ns
			MIL	20		30		30		
14	TISVKH	$\overline{IS}$ to K HIGH Setup Time (Note 6)	COM'L	15		25		30		ns
			MIL	20		30		35		
15	TKHISX	$\overline{IS}$ to K HIGH Hold Time (Note 6)	COM'L	0		0		0		ns
			MIL	0		0		0		

See also Switching Test Circuits.

Notes:
1. Tests are performed with input transition time of 5 ns or less, timing reference levels of 1.5 V, and input pulse levels of 0 to 3.0 V using test load in A. under Switching Test Circuits.
2. TGHQZ and TKHQZ are measured at steady state HIGH output voltage −0.5 V and steady state LOW output voltage +0.5 V output levels using the test load in B. under Switching Test Circuits.
3. Applies only when Asynchronous Enable ($\overline{G}$) function is used.
4. Applies only when Synchronous Enable ($\overline{GS}$) function has been programmed.
5. Applies only to the Am27S45 (Asynchronous Initialize ($\overline{I}$)) version.
6. Applies only to the Am27S47 (Synchronous Initialize ($\overline{IS}$)) version.
7. Minimum delay time is guaranteed by design and supported by characterization data.

*Subgroups 7 and 8 apply to functional tests.

SWITCHING TEST CIRCUITS



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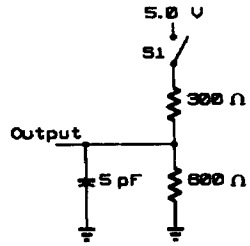
A. Output Load for all AC tests except TGHQZ and TKHQZ



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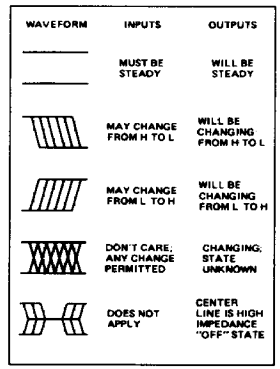
B. Output Load for TGHQZ and TKHQZ

Notes: 1. All device test loads should be located within 2" of device output pin.
2. S_1 is open for Output Data HIGH to Hi-Z and Hi-Z to Output Data HIGH tests. S_1 is closed for all other AC tests.
3. Load capacitance includes all stray and fixture capacitance.

SWITCHING WAVEFORMS

KEY TO SWITCHING WAVEFORMS



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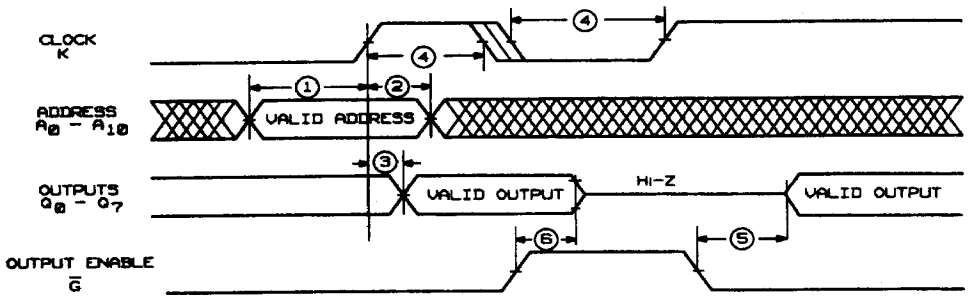
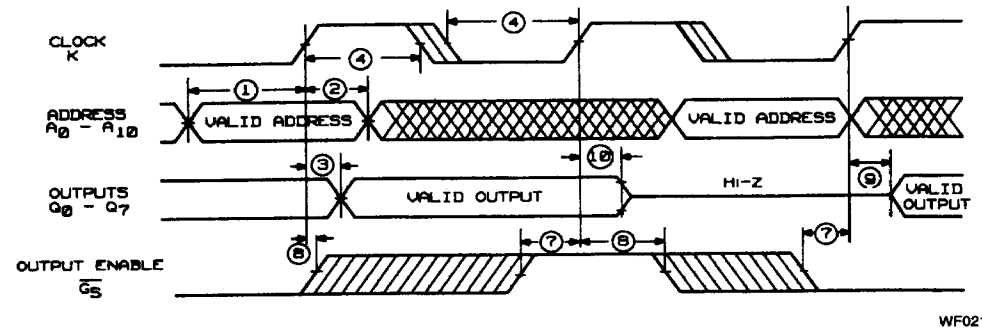


Timing Set 1. Using Asynchronous Enable



Timing Set 2. Using Synchronous Enable

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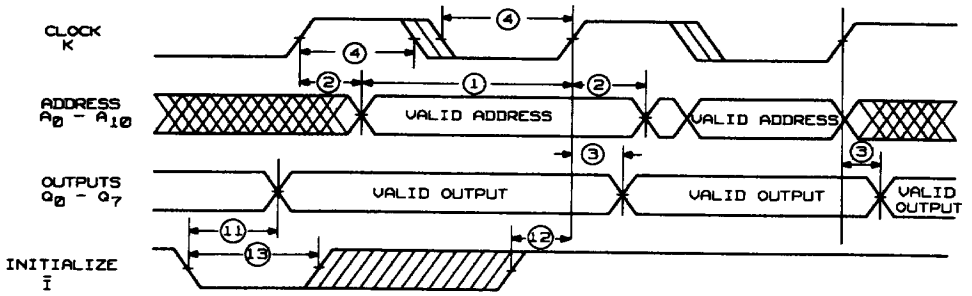

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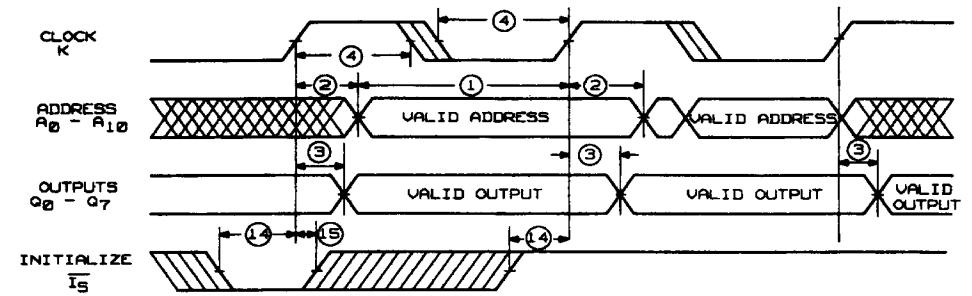
Timing Set 3. Using Asynchronous Initialize
Am27S45 Only



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Timing Set 4. Using Synchronous Initialize
Am27S47 Only